



# 14th International Conference on Nuclear Microprobe Technology and Applications

## Thursday, 10 July 2014

### Session 8 - Nuclear Microprobe Applications: Microelectronics - Auditorium (14:00 - 15:10)

-Conveners: Gyorgy Vizkelethy

time	[id] title	presenter
14:00	[13] Development of Diagnostic Method for Deep Levels in Semiconductors using Charge Induced by Heavy Ion Microbeams	Dr OHSHIMA, Takeshi
14:30	[42] Radiation Hardness of n-type SiC Schottky Diodes	Dr PASTUOVIC, Zeljko
14:50	[7] Ion Electron Emission Microscopy at LNL	Dr SILVESTRIN, Luca